

BS ISO/IEC 10373-6:2016



BSI Standards Publication

Identification cards — Test methods

Part 6: Proximity cards

National foreword

This British Standard is the UK implementation of ISO/IEC 10373-6:2016. It supersedes BS ISO/IEC 10373-6:2011+A4:2012 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee IST/17, Cards and personal identification.

A list of organizations represented on this committee can be obtained on request to its secretary.

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**Identification cards — Test
methods —**

**Part 6:
Proximity cards**

Cartes d'identification — Méthodes d'essai —

Partie 6: Cartes de proximité



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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work. In the field of information technology, ISO and IEC have established a joint technical committee, ISO/IEC JTC 1.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT) see the following URL: [Foreword - Supplementary information](#)

The committee responsible for this document is ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

This third edition cancels and replaces the second edition (ISO/IEC 10373-6:2011), which has been technically revised.

It also incorporates the Amendments ISO/IEC 10373-6:2011/Amd 1:2012, ISO/IEC 10373-6:2011/Amd 2:2012, ISO/IEC 10373-6:2011/Amd 3:2012, ISO/IEC 10373-6:2011/Amd 4:2012, and the Technical Corrigendum ISO/IEC 10373-6:2011/Cor 1:2013.

ISO/IEC 10373 consists of the following parts, under the general title *Identification cards — Test methods*:

- *Part 1: General characteristics*
- *Part 2: Cards with magnetic stripes*
- *Part 3: Integrated circuit cards with contacts and related interface devices*
- *Part 5: Optical memory cards*
- *Part 6: Proximity cards*

- *Part 7: Vicinity cards*
- *Part 8: USB-ICC*
- *Part 9: Optical memory cards — Holographic recording method*

Identification cards – Test methods – Part 6: Proximity cards

1 Scope

ISO/IEC 10373 defines test methods for characteristics of identification cards according to the definition given in ISO/IEC 7810. Each test method is cross-referenced to one or more base standards, which can be ISO/IEC 7810 or one or more of the supplementary standards that define the information storage technologies employed in identification card applications.

NOTE 1 Criteria for acceptability do not form part of ISO/IEC 10373, but will be found in the International Standards mentioned above.

NOTE 2 Test methods defined in this part of ISO/IEC 10373 are intended to be performed separately. A given proximity card or object, or proximity coupling device, is not required to pass through all the tests sequentially.

This part of ISO/IEC 10373 defines test methods which are specific to proximity cards and objects, and proximity coupling devices and proximity extended devices, defined in ISO/IEC 14443-1, ISO/IEC 14443-2, ISO/IEC 14443-3, and ISO/IEC 14443-4.

ISO/IEC 10373-1 defines test methods which are common to one or more integrated circuit card technologies and other parts deal with other technology-specific tests.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC 7810, *Identification cards — Physical characteristics*

ISO/IEC 14443-1:2016, *Identification cards — Contactless integrated circuit cards — Proximity cards — Part 1: Physical characteristics*

ISO/IEC 14443-2:2016, *Identification cards — Contactless integrated circuit cards — Proximity cards — Part 2: Radio frequency power and signal interface*

ISO/IEC 14443-3:2016, *Identification cards — Contactless integrated circuit cards — Proximity cards — Part 3: Initialization and anticollision*

ISO/IEC 14443-4:2016, *Identification cards — Contactless integrated circuit cards — Proximity cards — Part 4: Transmission protocol*

IEC 61000-4-2:2008, *Electromagnetic compatibility (EMC) — Part 4-2: Testing and measurement techniques — Electrostatic discharge immunity test*